

\* Vibration test  $10 \sim 50 \sim 10$  Hz sweeped in 60 seconds X,Y,Z direction 1 hour each direction Result: No dislodgement of the cell or damage No discontinuity over 10 micro-seconds.

\* Soldering per JSTD020C Table 4.1

\* Drop Test:

Mounted on board and dropped 5 times from 1m high to concrete floor Result: NO dislodgement of the cell, No damage to the holders

\* Shock Test: Half sine wave acceleration 150G. 6 micro-seconds. X,Y,Z direction 3 times each direction

Result: No dislodgement of cell No damage to the holder.

\* Temperature resistance test: 80°C 168 hours with battery on

Result: Contact resistance- below 100m ohms Insulation resistance—over 100m ohms.

\* Temperature shock test: -30°C< >80°C 1hours 100cycles

Contact resistance- below 100m ohms Insulation resistance-over 100m ohms

Voltage resistance- No damage.

\* ROHS COMPLIANT

PATENT NO. 5,922,489

Tolerance (Except as noted)	Memory Protection Devices, Inc 200 Broad Hollow Road, Farmingdale, New York 11735			
decimal			Scale	Drawn By T.S.
±.5 (.020)			2=1	Approved By T.B.
Fractional ± .8 (.030)	Title COIN CELL HOLDER			
Angular	Date Drawing Nu		ımber	
± 3°	6/27/08	BA2032		